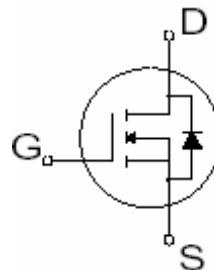


- Extremely high dv/dt capability
- Low Gate Charge Qg results in Simple Drive Requirement
- 100% avalanche tested
- Gate charge minimized
- Very low intrinsic capacitances
- Very good manufacturing repeatability



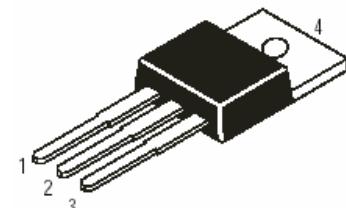
**V<sub>DSS</sub> = 900V**

**I<sub>D25</sub> = 4A**

**R<sub>DSON</sub> = 4.2 Ω**

## Description

StarMOS is a new generation of high voltage N-Channel enhancement mode power MOSFETs. This new technology minimises the JFET effect, increases packing density and reduces the on-resistance. StarMOS also achieves faster switching speeds through optimised gate layout with planar stripe DMOS technology.



Pin1-Gate  
Pin2-Drain  
Pin3-Source

## Application

- Switching application

## Absolute Maximum Ratings

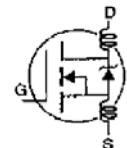
	Parameter	Max.	Units
I <sub>D</sub> @T <sub>c</sub> =25°C	Continuous Drain Current,V <sub>GS</sub> @10V	4	A
I <sub>D</sub> @T <sub>c</sub> =100°C	Continuous Drain Current,V <sub>GS</sub> @10V	2.3	
I <sub>DM</sub>	Pulsed Drain Current ①	16	
P <sub>D</sub> @T <sub>c</sub> =25°C	Power Dissipation	140	W
	Linear Derating Factor	1.12	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	±30	V
E <sub>AS</sub>	Single Pulse Avalanche Energy ②	170	mJ
I <sub>AR</sub>	Avalanche Current ①	2.2	A
E <sub>AR</sub>	Repetitive Avalanche Energy ①	8.5	mJ
dv/dt	Peak Diode Recovery dv/dt ③	4.0	V/ns
T <sub>J</sub>	Operating Junction and Storage Temperature Range	-55 to +150	C
T <sub>STG</sub>	Soldering Temperature, for 10 seconds	300(1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw	10 lbf.in(1.1N.m)	

## Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
R <sub>θJC</sub>	Junction-to-case	—	—	0.89	C/W
R <sub>θCS</sub>	Case-to-Sink, Flat, Greased Surface	—	0.5	—	
R <sub>θJA</sub>	Junction-to-Ambient	—	—	62.5	

### Electrical Characteristics @TJ=25°C(unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	900	—	—	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA
△V <sub>(BR)DSS</sub> /△T <sub>J</sub>	Breakdown Voltage Temp.Coefficient	—	1.05	—	V/C	Reference to 25°C, I <sub>D</sub> =250μA
R <sub>D(on)</sub>	Static Drain-to-Source On-resistance	—	3.5	4.2	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =2A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	3.0	—	5.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA
g <sub>fs</sub>	Forward Transconductance	—	2.0	—	S	V <sub>DS</sub> =50V, I <sub>D</sub> =2A
I <sub>DSS</sub>	Drain-to-Source Leakage current	—	—	10	μ A	V <sub>DS</sub> =900V, V <sub>GS</sub> =0V
		—	—	100	μ A	V <sub>DS</sub> =720V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C
I <sub>GSS</sub>	Gate-to-Source Forward leakage	—	—	100	nA	V <sub>GS</sub> =30V
	Gate-to-Source Reverse leakage	—	—	-100	nA	V <sub>GS</sub> =-30V
Q <sub>g</sub>	Total Gate Charge	—	17	22		I <sub>D</sub> =4A
Q <sub>gs</sub>	Gate-to-Source charge	—	4.5	—		V <sub>DS</sub> =720V
Q <sub>gd</sub>	Gate-to-Drain("Miller") charge	—	7.5	—		V <sub>GS</sub> =10V See Fig.6 and 13④
t <sub>d(on)</sub>	Turn-on Delay Time	—	25	60		V <sub>DD</sub> =450V
t <sub>r</sub>	Rise Time	—	50	110		I <sub>D</sub> =4A
t <sub>d(off)</sub>	Turn-Off Delay Time	—	40	90		R <sub>G</sub> =25Ω
t <sub>f</sub>	Fall Time	—	35	80		
L <sub>D</sub>	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm(0.25in.) from package and center of die contact
L <sub>S</sub>	Internal Source Inductance	—	7.5	—		
C <sub>iss</sub>	Input Capacitance	—	740	960		V <sub>GS</sub> =0V
C <sub>oss</sub>	Output Capacitance	—	65	85	pF	V <sub>DS</sub> =25V
C <sub>rss</sub>	Reverse Transfer Capacitance	—	5.6	7.3		t=1.0MHz See Figure 5



### Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I <sub>s</sub>	Continuous Source Current (Body Diode)	—	—	4	A	MOSFET symbol showing the integral reverse p-n junction diode.
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	16		
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.4	V	T <sub>J</sub> =25°C, I <sub>s</sub> =4A, V <sub>GS</sub> =0V ④
t <sub>rr</sub>	Reverse Recovery Time	—	450	—	nS	T <sub>J</sub> =25°C, I <sub>s</sub> =4A
Q <sub>rr</sub>	Reverse Recovery Charge	—	3.5	—	nC	di/dt=100A/μs ④
t <sub>on</sub>	Forward Turn-on Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>s</sub> + L <sub>d</sub> )				

#### Notes:

- ① Repetitive rating;pulse width limited by max.junction temperature(see figure 11)
- ② L = 67mH, I<sub>AS</sub> = 4A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25Ω, Starting T<sub>J</sub> = 25°C

③ I<sub>SD</sub>≤4A,di/dt≤200A/μs,V<sub>DD</sub>≤V<sub>(BR)DSS</sub>, T<sub>J</sub>≤25°C

④ Pulse width≤300 μs; duty cycle≤2%